

**Search Notes (continued)****Application/Control No.**

10/780,990

**Examiner**

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**Applicant(s)/Patent under Reexamination**

BENTLEY ET AL.

**Art Unit**

2825

**SEARCHED**

Class	Subclass	Date	Examiner
716	11	6/26/2006	JSL
716	15	6/26/2006	JSL
716	1	6/26/2006	JSL
700	121	6/26/2006	JSL
700	97	6/26/2006	JSL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST [USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB]	6/26/2006	JSL
EAST [USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB]	6/27/2006	JSL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner